

Search Notes



Application/Control No.

10/811.807

Examiner

Tod T. Van Roy

**Applicant(s)/Patent under
Reexamination**

YUN, SANG BOK

Art Unit

2828

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Please see search history attached		
Spoke with examiner James Merete regarding gaps near facets	3/2/05	
Spoke with examiner James Merete regarding wet/dry etching	3/3/05	